


<b>Search Notes</b>  	<b>Application/Control No.</b>  10517623	<b>Applicant(s)/Patent Under Reexamination</b>  YABE ET AL.
	<b>Examiner</b>  Kim, Hee Soo	<b>Art Unit</b>  2157

SEARCHED			
Class	Subclass	Date	Examiner
709	206	6/24/2008	HSK

SEARCH NOTES		
Search Notes	Date	Examiner
Updated East Search	6/24/2008	HSK

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner